



SCANNING ELECTRON MICROSCOPE (SEM)

MANUFACTURER : JEOL

MODEL : JSM 7401F

Samples

- Sample size: 150 mm maximum
- Thickness: 5 mm maximum

Analysis

- Acceleration: 0.1 keV to 30 keV
- Resolution : about 1 nm

Variants

- Phase analysis by backscattered electron detection
- Energy Dispersive Spectrometer (EDS) for X-ray elemental analysis